

Amendments to the Claims:

The following listing of claims will replace all prior versions, and listings, of claims in the application:

- 1-2. (Canceled)
3. (Currently Amended) ~~The analog/digital characteristics testing device as claimed in claim 2, wherein~~ An analog/digital characteristics testing device comprising:
a plurality of measurement circuits for measuring an analog/digital
characteristic of one or more ICs to be tested in accordance with a test condition data; and
a setting unit for setting a different test condition data to each measurement
circuit; and
wherein the setting unit comprises:
a test condition outputting circuit for outputting the test condition data in
order;
a counting circuit for counting the number of the test condition data outputted
from the test condition outputting circuit; and
a specifying circuit for specifying the measurement circuit in which the test
condition data is written, in accordance with a counter value of the counting circuit; and
when an initial test condition data is outputted from the test condition
outputting circuit, the specifying circuit specifies all of the measurement circuits as a circuit
in which the initial test condition data is written, and
when a counter value counted by the counting circuit is equivalent to the
number of the measurement circuit, the specifying circuit specifies the measurement circuits
where the test condition data written to each measurement circuit is different from one
another, at a point when the test condition outputting circuit finishes outputting the test
condition data.

4. (Currently Amended) The analog/digital characteristics testing device as claimed in claim 13, further comprising a management unit for managing a test result data obtained by each measurement circuit.

5. (Currently Amended) The analog/digital characteristics testing device as claimed in claim 4, wherein the setting unit comprises:

a test condition outputting circuit for outputting the test condition data in order; and

a counting circuit for counting the number of the test condition data outputted from the test condition outputting circuit; and wherein

the management unit comprises:

a multiplexing circuit for outputting the test result data obtained by each measurement circuit, from a predetermined output terminal in accordance with ~~at~~the counter value of the counting circuit; and

a judging circuit for judging whether the one or more ICs to be tested are good or poor in accordance with the test result data outputted from the multiplexing circuit; and

when the counter value is 1, the multiplexing circuit outputs the test result data respectively from the predetermined output terminals, and when the counter value is equivalent to the number of the measurement circuits, the multiplexing circuit operates an AND operation of the test result data and outputs a computed result obtained by the AND operation from the predetermined output terminal.

6-10. (Canceled)

11. (Currently Amended) ~~The IC testing apparatus as claimed in claim 10,~~
wherein An IC testing apparatus comprising:

an analog/digital characteristics testing device comprising:

a plurality of measurement circuits for measuring an analog/digital
characteristic of one or more ICs to be tested in accordance with a test condition data; and
a setting unit for setting a different test condition data to each measurement
circuit; and
wherein the setting unit comprises:
a test condition outputting circuit for outputting the test condition data in
order;
a counting circuit for counting the number of the test condition data outputted
from the test condition outputting circuit; and
a specifying circuit for specifying the measurement circuit in which the test
condition data is written, in accordance with a counter value of the counting circuit; and
when an initial test condition data is outputted from the test condition
outputting circuit, the specifying circuit specifies all of the measurement circuits as a circuit
in which the initial test condition data is written; and
when a counter value counted by the counting circuit is equivalent to the
number of the measurement circuit, the specifying circuit specifies the measurement circuits
where the test condition data written to each measurement circuit is different from one
another, at a point when the test condition outputting circuit finishes outputting the test
condition data.

12. (Currently Amended) The IC testing apparatus as claimed in claim 911, wherein the analog/digital characteristics testing device further comprises a management unit for managing a test result data obtained by each measurement circuit.

13. (Currently Amended) The IC testing apparatus as claimed in claim 12, wherein the setting unit comprises:

a test condition outputting circuit for outputting the test condition data in order; and

a counting circuit for counting the number of the test condition data outputted from the test condition outputting circuit; and wherein

the management unit comprises:

a multiplexing circuit for outputting the test result data obtained by each measurement circuit, from a predetermined output terminal in accordance with athe counter value of the counting circuit; and

a judging circuit for judging whether the one or more ICs to be tested are good or poor in accordance with the test result data outputted from the multiplexing circuit; and wherein

when the counter value is 1, the multiplexing circuit outputs the test result data respectively from the predetermined output terminals, and when the counter value is equivalent to the number of the measurement circuits, the multiplexing circuit operates an AND operation of the test result data and outputs a computed result obtained by the AND operation from the predetermined output terminal.

14-16. (Canceled)